

## Abstract Example

*Please Note: this is just an example; it is not a requirement to follow this outline*

1. **Title of Paper:** How to reduce the overall cost of testing Power Management ICs (PMICs) on the V93000
2. **Motivation/Problem Statement: Why do we care about the topic? What is the goal of this paper?**  
**Goal:** Minimizing the production test time for any device is a key financial metric to the product release. This paper will show how to test 16 PMIC devices in 5 seconds in a production test flow.
3. **Methods/Procedure/Approach: What topics will your paper cover? How do we achieve this?**
  - a. Test list by IP block
  - b. Key methodologies that allow us to achieve the desired goal
    - i. Smart Calc – theory and code examples
    - ii. Testing IPs in parallel for each site – theory and code examples
    - iii. Using DC Scale anchor points to make pattern-based measurements – theory
    - iv. Using Smart RDI as a user-friendly way for pattern-based measurements – theory and code examples
  - c. DUT board considerations
    - i. Layout of the multi-site that helps to improve accuracy and reduce wait times
    - ii. Other special things done – what and why
4. **Results/Findings/Product: As a result of completing the above procedure, what are the results and what did you learn/invent/create?**  
**Results:**
  - a. Achieved this test time or possibly a reduction in percentage or test time over previous methods
    - i. Breakdown of test time if possible
  - b. What other benefits were achieved with the lower test time?
    - i. Better utilization of tester HW
5. **Conclusion/Implications: What are the larger implications of your findings, especially for the problem/gap identified in step 2?**  
**Conclusion:**
  - a. Very high-level summary of results
    - i. Went from test time x to test time y
    - ii. What are the biggest contributors to the test time reductions?
  - b. I discovered these things throughout the development process
    - i. System and software learnings
    - ii. Device learnings
  - c. Next time I am going to do these things differently
    - i. Reorganize the test flow
    - ii. Use this new feature
    - iii. Try this different test methodology where I expect these benefits